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دانشکده مهندسی کامپیوتر

تمرین هفتم درس روش پژوهش و ارائه

استاد: دکتر رضا صفابخش

تهیه کننده: بردیا اردکانیان

برسی و مهار مثال‌های خصمانه در یادگیری ماشین

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